Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/500,603	OOSAWA ET AL.	
Examiner	Art Unit	
Devin Hanan	3745	

	SEARCHED		
Class	Subclass	Date	Examiner
415	199.5		
	60,66		
416	20,128		
	198R	10/28/2005	DH

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		-	
	1.		

SEARCH (INCLUDING SEAR	NOTES CH STRATEGY	')
	DATE	EXMR
consulted Ninh Nguyen on class 415 and 416	10/26/2005	DH